Substitute form 1449A/PTO			Complete if Known		
			Application Number	To Be Assigned 101796672	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Filing Date	Concurrently Herewith 319 2004	
			First Named Inventor	Young-pil Kim et al.	
			Group Art Unit	Unknown 20 5	
			Examiner Name	Hoknowi Landau	
Sheet 1	of	1	Attorney Docket Number	5649-1276	

Sneet	17	<u> OT 1</u>		Attorney Docket Number 5649-1	2/6
				AND PATENT PUBLICATIONS	
Examiner Initials*	Cite No	U.S. Patent D	ocument	Name of Patentee or Applicant of Cite	ed Date of Publication of Cited
		Number	Kind Code (if known)	Document	Document MM-DD-YYYY
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		OTHER NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	Τ.
Mh	1	Young Pil Kim et al., "Rellability Degradation of High Density DRAM Cell Transistor Junction Leakage Current Induced by Band-to-Defect tunneling Under the Off-State Bias-Temperature Stress," IEEE, 2001	
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Examiner Signature	Marker C. Janker	Date Considered	7/16/06

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.